

Notice of References Cited	Application/Control No. 10/708,553	Applicant(s)/Patent Under Reexamination HU ET AL.	
	Examiner BRIAN P. YENKE	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0042039	03-2004	Kodera et al.	358/001.15
*	B	US-2003/0001981	01-2003	Milne, James R.	348/839
*	C	US-2002/0118315	08-2002	Hong, Joo-sun	348/839
*	D	US-7,116,379	10-2006	Suzuki, Masayuki	348/747
*	E	US-7,019,792	03-2006	Kimura, Keishi	348/744
*	F	US-7,003,172	02-2006	Takeuchi et al.	382/254
*	G	US-7,220,006	05-2007	Allen et al.	353/85
*	H	US-6,958,760	10-2005	Kim, Young-Sun	345/697
*	I	US-6,793,347	09-2004	Morishita, Isaya	353/119
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.